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Contents

vii *Conference Committee*

SESSION 1 NEW METHODS AND ADVANCED PHOTONICS

12997 05 **Image flow-cytometry meets virtual reality: a new scenario for label-free quantitative phase contrast microscopy and single cell analysis** [12997-4]

12997 07 **In-process detection of laser-generated ultrasound for controlling material laser processing** [12997-6]

12997 08 **Application of frequency-shifted feedback laser optical frequency combs for distance and refraction coefficient measurements** [12997-7]

SESSION 2 INTERFEROMETRY AND HOLOGRAPHY

12997 0A **Zoom system for coherent imaging with no moving lens groups** [12997-9]

12997 0B **In vivo investigation of anuran sound localization with achiral digital Fresnel holography** [12997-10]

SESSION 3 INTERFEROMETRY FOR TOPOGRAPHY AND SHAPE

12997 0E **Analysis and improvement of the lateral resolution of CSI instruments based on the universal Fourier optics (UFO) model (Invited Paper)** [12997-13]

12997 0F **Multispectral interferometry for characterizing nano-objects** [12997-14]

12997 0G **Refocus criterion in dual-wavelength digital holographic interferometry for accurate shape measurement** [12997-15]

12997 0H **Suppression of scanning nonlinearities through computational self-correction in optical profilometry** [12997-16]

SESSION 4 INTERFEROMETRY FOR DISTANCES, WAVEFRONTS, AND FORM

12997 0I **James C. Wyant** [12997-17]

12997 0J **Multiplexing interferometers using range-resolved interferometry (Invited Paper)** [12997-18]

12997 0L **Interferometer cosine error and uncertainty minimisation using an external cavity** [12997-20]

SESSION 5 CONFOCAL, SPECKLE, AND SPECTRAL METROLOGY

12997 0M **Digital twins for 3D confocal microscopy** [12997-21]

12997 0N **Universal Fourier optics model for virtual confocal microscopes** [12997-22]

12997 0O **Implementations of ESFS for fast topographic acquisition** [12997-23]

12997 0P **Speckle pattern optimization in laser speckle photometry for non-destructive testing** [12997-24]

12997 0Q **Inline inspection of coating thickness on polymers using infrared reflection-absorption spectroscopy** [12997-25]

12997 0R **Advancements in metrology for advanced semiconductor packaging** [12997-26]

SESSION 6 BIG SCIENCE: GRAVITY WAVES, TELESCOPES, UV OPTICS

12997 0S **The laser interferometer space antenna (LISA) (Invited Paper)** [12997-27]

12997 0T **Achieving a cosmological reach: from advanced LIGO to the next generation of terrestrial gravitational wave detectors (Invited Paper)** [12997-28]

12997 0U **Rigid body motion tracking in axial shift mapping for measuring astronomical x-ray mirror figure (Invited Paper)** [12997-29]

SESSION 7 AI, MACHINE LEARNING, AND COMPUTATIONAL IMAGING

12997 0X **Evaluating autofocusing metrics in digital lensless holographic microscopy** [12997-32]

12997 0Y **Correlating machine vision and learning with robot handling in increasing productivity of airbags manufacturing** [12997-33]

12997 0Z **Dynamic mode decomposition-based algorithm for phase-shifting interferometry in the presence of miscalibration and vibration** [12997-34]

SESSION 8 DEFLECTOMETRY AND FRINGE PROJECTION

12997 10 **Deep-learning-enabled temporally super-resolved multiplexed fringe projection profilometry: high-speed kHz 3D imaging with low-speed camera** [12997-35]

12997 11 **Gamma correction in simultaneously dual fringe projection moiré profilometry** [12997-36]

12997 13 **Phase measuring deflectometry with monoscopic active display registration** [12997-38]

POSTER SESSION

12997 16 **Phase-shifting algorithm using a single interferogram and deep learning** [12997-41]

12997 17 **Influence of specimen positioning stage drift in tilted-wave interferometry for accurate form measurements for aspherical and freeform surfaces** [12997-42]

12997 18 **Interferometric method for characterizing optical retarders** [12997-43]

12997 1A **Tilt-to-length coupling metrology in the LISA mission** [12997-45]

12997 1B **Diffractio: an open-source library for diffraction and interference calculations** [12997-46]

12997 1G **A digital holographic system for measuring bacterial growth in micro-fluidic chambers** [12997-51]

12997 1H **Uncertainty on Brillouin frequency on bulk polymethyl methacrylate for acoustic waves velocities** [12997-52]

12997 1I **Differential confocal microscopy for stable scanning-microsphere assisted direct laser writing** [12997-53]

12997 1K **Technological challenges in the measurement of photonic products with white light interferometry** [12997-55]

12997 1L **OpenRRI: theory and application of open-source interferometry** [12997-56]

12997 1M **A comparison of inspections using an on-machine tactile probe and in situ laser tracker in shop floor conditions** [12997-57]

12997 1N **Towards online monitoring of water pollutants: an optofluidic chip for characterizing microplastics in water (Best Student Paper Award)** [12997-58]

12997 1P **Fourier-Bessel series expansion-based fringe pattern denoising and inpainting** [12997-63]

DIGITAL POSTER SESSION

12997 1Q **Scatterometry of nano-particles on silicon wafer** [12997-60]

12997 1R **Light scattering defects and measurement accuracy in cavity ring-down spectroscopy** [12997-61]

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